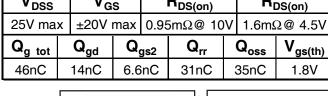
# International IOR Rectifier

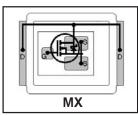
# IRF6717MPbF IRF6717MTRPbF

DirectFET™ Power MOSFET ②

Typical valu	ies (unless	otherwise	specifie	ed)

V <sub>DSS</sub>	V <sub>G</sub>	s	R <sub>DS(on)</sub>		R	R <sub>DS(on)</sub>		
25V ma	x ±20V	max	0.95	$5$ m $\Omega$ @ 10	)V 1.6m	Ω@ 4.5V		
Q <sub>g tot</sub>	$\mathbf{Q}_{gd}$	Q	gs2	Q <sub>rr</sub>	Q <sub>oss</sub>	V <sub>gs(th)</sub>		
46nC	14nC	6.6	nC	31nC	35nC	1.8V		







RoHs Compliant and Halgen Free ①

• Low Profile (<0.7 mm)

• Dual Sided Cooling Compatible ①

Ultra Low Package Inductance

Optimized for High Frequency Switching ①

• Ideal for CPU Core DC-DC Converters

• Optimized for Sync. FET socket of Sync. Buck Converter ①

Low Conduction and Switching Losses

Compatible with existing Surface Mount Techniques ①

●100% Rg tested

Applicable DirectFET Outline and Substrate Outline (see p.7,8 for details) □

Ī	SQ	SX	ST	MQ	MX	MT	MP		
		-	_						

#### **Description**

The IRF6717MPbF combines the latest HEXFET® Power MOSFET Silicon technology with the advanced DirectFET™ packaging to achieve the lowest on-state resistance in a package that has the footprint of a SO-8 and only 0.7 mm profile. The DirectFET package is compatible with existing layout geometries used in power applications, PCB assembly equipment and vapor phase, infra-red or convection soldering techniques, when application note AN-1035 is followed regarding the manufacturing methods and processes. The DirectFET package allows dual sided cooling to maximize thermal transfer in power systems, improving previous best thermal resistance by 80%.

The IRF6717MPbF balances both low resistance and low charge along with ultra low package inductance to reduce both conduction and switching losses. The reduced total losses make this product ideal for high efficiency DC-DC converters that power the latest generation of processors operating at higher frequencies. The IRF6717MPbF has been optimized for parameters that are critical in synchronous buck including Rds(on), gate charge and Cdv/dt-induced turn on immunity. The IRF6717MPbF offers particularly low Rds(on) and high Cdv/dt immunity for synchronous FET applications.

**Absolute Maximum Ratings** 

	Parameter	Max.	Units
V <sub>DS</sub>	Drain-to-Source Voltage	25	V
$V_{GS}$	Gate-to-Source Voltage	±20	
I <sub>D</sub> @ T <sub>A</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V ③	38	
I <sub>D</sub> @ T <sub>A</sub> = 70°C	Continuous Drain Current, V <sub>GS</sub> @ 10V ③	30	Α
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V @	220	
I <sub>DM</sub>	Pulsed Drain Current ®	300	
E <sub>AS</sub>	Single Pulse Avalanche Energy ©	290	mJ
I <sub>AR</sub>	Avalanche Current ©	30	Α

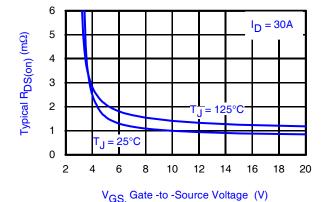


Fig 1. Typical On-Resistance vs. Gate Voltage

- ① Click on this section to link to the appropriate technical paper.
- ② Click on this section to link to the DirectFET Website.
- 3 Surface mounted on 1 in. square Cu board, steady state.

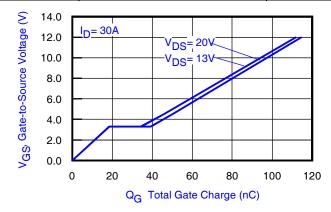


Fig 2. Typical Total Gate Charge vs Gate-to-Source Voltage

- 4 T<sub>C</sub> measured with thermocouple mounted to top (Drain) of part.
- S Repetitive rating; pulse width limited by max. junction temperature.
- © Starting  $T_J = 25$ °C, L = 0.64mH,  $R_G = 25\Omega$ ,  $I_{AS} = 30$ A.

### Static @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
BV <sub>DSS</sub>	Drain-to-Source Breakdown Voltage	25			V	$V_{GS} = 0V, I_{D} = 250\mu A$
$\Delta BV_{DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		18		mV/°C	Reference to 25°C, I <sub>D</sub> = 1mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance		0.95	1.25	mΩ	V <sub>GS</sub> = 10V, I <sub>D</sub> = 38A ⑦
			1.6	2.1		$V_{GS} = 4.5V, I_{D} = 30A$ ⑦
$V_{GS(th)}$	Gate Threshold Voltage	1.35	1.8	2.35	V	$V_{DS} = V_{GS}$ , $I_D = 150\mu A$
$\Delta V_{GS(th)}/\Delta T_{J}$	Gate Threshold Voltage Coefficient		-6.7		mV/°C	
I <sub>DSS</sub>	Drain-to-Source Leakage Current			1.0	μΑ	$V_{DS} = 20V, V_{GS} = 0V$
				150		$V_{DS} = 20V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I <sub>GSS</sub>	Gate-to-Source Forward Leakage			100	nA	$V_{GS} = 20V$
	Gate-to-Source Reverse Leakage			-100		V <sub>GS</sub> = -20V
gfs	Forward Transconductance	140			S	$V_{DS} = 13V, I_{D} = 30A$
$Q_g$	Total Gate Charge		46	69		
$Q_{gs1}$	Pre-Vth Gate-to-Source Charge		14			$V_{DS} = 13V$
$Q_{gs2}$	Post-Vth Gate-to-Source Charge		6.6		nC	$V_{GS} = 4.5V$
$Q_gd$	Gate-to-Drain Charge		14			$I_D = 30A$
$Q_{godr}$	Gate Charge Overdrive		11			See Fig. 15
$Q_{sw}$	Switch Charge (Q <sub>gs2</sub> + Q <sub>gd</sub> )		20.6			
Q <sub>oss</sub>	Output Charge		35		nC	$V_{DS} = 16V, V_{GS} = 0V$
$R_{G}$	Gate Resistance		1.3	2.2	Ω	
t <sub>d(on)</sub>	Turn-On Delay Time		25			$V_{DD} = 13V, V_{GS} = 4.5V$ ⑦
t <sub>r</sub>	Rise Time		37			$I_D = 30A$
t <sub>d(off)</sub>	Turn-Off Delay Time		19		ns	$R_G = 1.8\Omega$
t <sub>f</sub>	Fall Time		15			
C <sub>iss</sub>	Input Capacitance		6750			$V_{GS} = 0V$
C <sub>oss</sub>	Output Capacitance		1700		pF	$V_{DS} = 13V$
C <sub>rss</sub>	Reverse Transfer Capacitance		730			f = 1.0MHz

#### **Diode Characteristics**

Diouc (	blode Characteristics								
	Parameter	Min.	Тур.	Max.	Units	Conditions			
Is	Continuous Source Current			120		MOSFET symbol			
	(Body Diode)				Α	showing the			
I <sub>SM</sub>	Pulsed Source Current			300		integral reverse			
	(Body Diode) ⑤					p-n junction diode.			
$V_{SD}$	Diode Forward Voltage			1.0	V	$T_J = 25^{\circ}C, I_S = 30A, V_{GS} = 0V                                  $			
t <sub>rr</sub>	Reverse Recovery Time		27	41	ns	$T_J = 25^{\circ}C, I_F = 30A$			
Q <sub>rr</sub>	Reverse Recovery Charge		31	47	nC	di/dt = 175A/µs ⑦			

#### Notes:

⑤ Repetitive rating; pulse width limited by max. junction temperature.

 $\ \$  Pulse width  $\le 400 \mu s$ ; duty cycle  $\le 2\%$ .

**Absolute Maximum Ratings** 

	Parameter	Max.	Units
P <sub>D</sub> @T <sub>A</sub> = 25°C	Power Dissipation ③	2.8	W
P <sub>D</sub> @T <sub>A</sub> = 70°C	Power Dissipation ③	1.8	
P <sub>D</sub> @T <sub>C</sub> = 25°C	Power Dissipation ④	96	
T <sub>P</sub>	Peak Soldering Temperature	270	°C
$T_J$	Operating Junction and	-40 to + 150	
T <sub>STG</sub>	Storage Temperature Range		

**Thermal Resistance** 

	Parameter	Тур.	Max.	Units
$R_{\theta JA}$	Junction-to-Ambient 3®		45	
$R_{\theta JA}$	Junction-to-Ambient ®®	12.5		
$R_{\theta JA}$	Junction-to-Ambient 90	20		°C/W
$R_{\theta JC}$	Junction-to-Case 4 10		1.3	
$R_{\theta J\text{-PCB}}$	Junction-to-PCB Mounted	1.0		
	Linear Derating Factor ③	0.0	022	W/°C

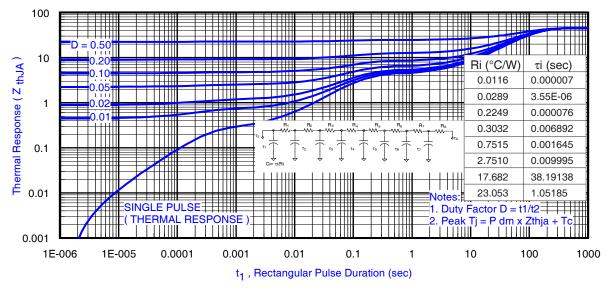
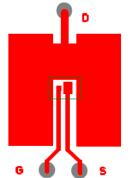


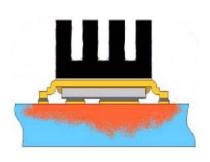
Fig 3. Maximum Effective Transient Thermal Impedance, Junction-to-Ambient ①

#### Notes:

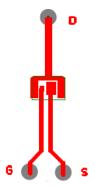
- ® Used double sided cooling, mounting pad with large heatsink.
- Mounted on minimum footprint full size board with metalized back and with small clip heatsink.
- $\ \ \, \mathbb{O} \ \ \, \mathsf{R}_{\theta}$  is measured at  $\mathsf{T}_{\mathsf{J}}$  of approximately 90°C.



③ Surface mounted on 1 in. square Cu (still air).



 Mounted to a PCB with small clip heatsink (still air)



 Mounted on minimum footprint full size board with metalized back and with small clip heatsink (still air)

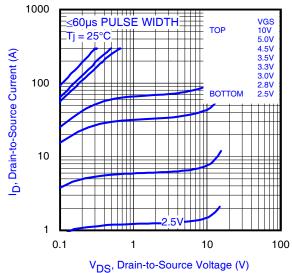


Fig 4. Typical Output Characteristics

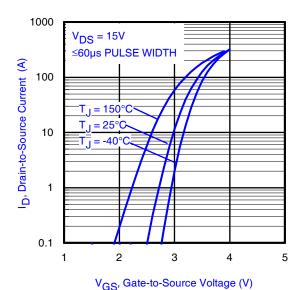


Fig 6. Typical Transfer Characteristics

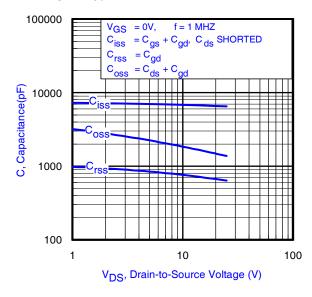


Fig 8. Typical Capacitance vs.Drain-to-Source Voltage

4

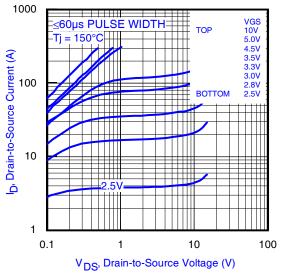


Fig 5. Typical Output Characteristics

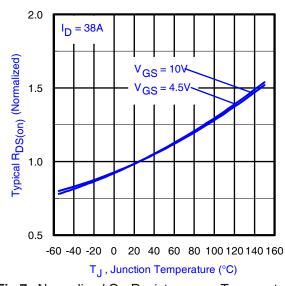
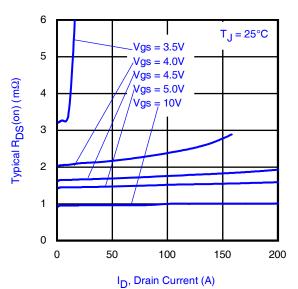


Fig 7. Normalized On-Resistance vs. Temperature



**Fig 9.** Typical On-Resistance vs. Drain Current and Gate Voltage

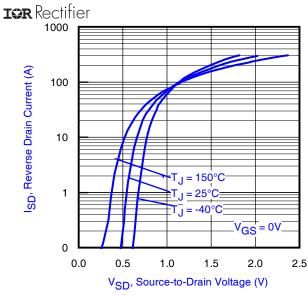


Fig 10. Typical Source-Drain Diode Forward Voltage

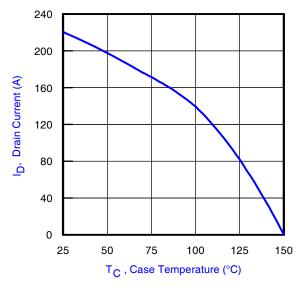


Fig 12. Maximum Drain Current vs. Case Temperature

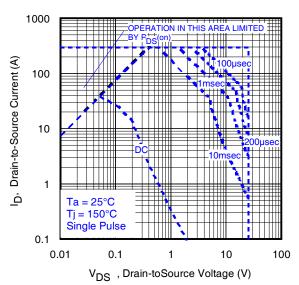


Fig11. Maximum Safe Operating Area

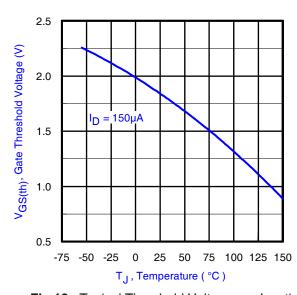


Fig 13. Typical Threshold Voltage vs. Junction Temperature

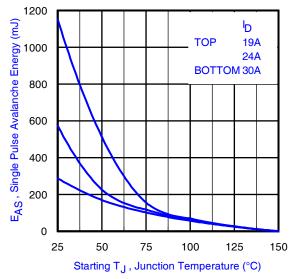


Fig 14. Maximum Avalanche Energy vs. Drain Current

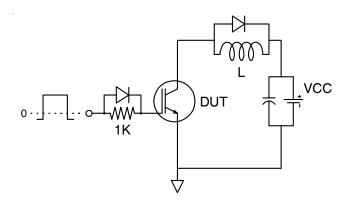


Fig 15a. Gate Charge Test Circuit

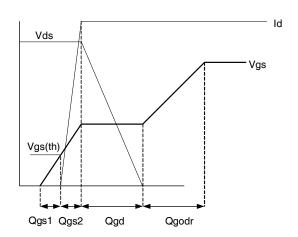


Fig 15b. Gate Charge Waveform

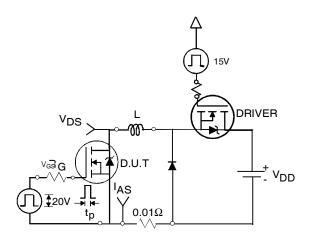


Fig 16a. Unclamped Inductive Test Circuit

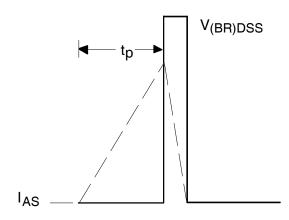


Fig 16b. Unclamped Inductive Waveforms

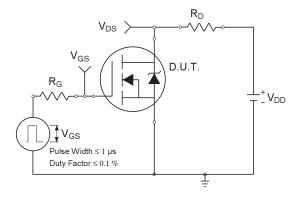


Fig 17a. Switching Time Test Circuit

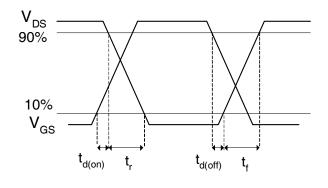


Fig 17b. Switching Time Waveforms

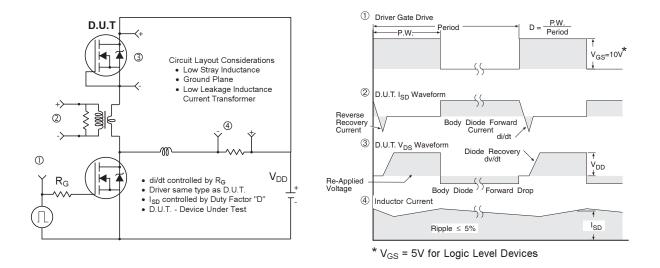
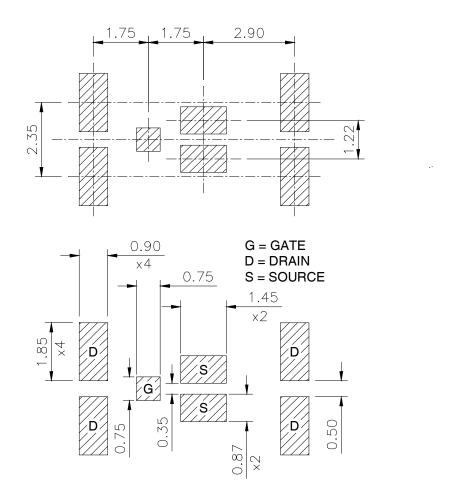


Fig 18. Diode Reverse Recovery Test Circuit for N-Channel HEXFET® Power MOSFETs

# DirectFET™ Board Footprint, MX Outline (Medium Size Can, X-Designation).

Please see DirectFET application note AN-1035 for all details regarding the assembly of DirectFET.

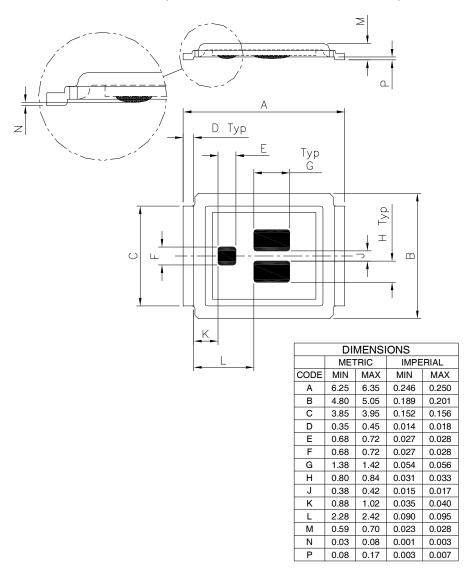
This includes all recommendations for stencil and substrate designs.



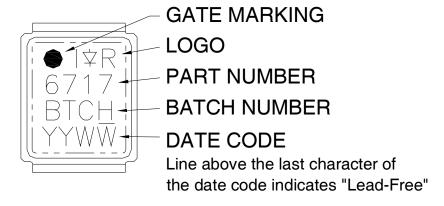
www.irf.com 7

DirectFET™ Outline Dimension, MX Outline (Medium Size Can, X-Designation).

Please see AN-1035 for DirectFET assembly details and stencil and substrate design recommendations

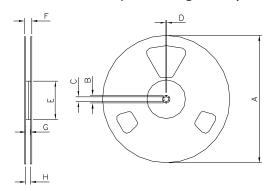


## DirectFET™ Part Marking



Note: For the most current drawing please refer to IR website at <a href="http://www.irf.com/package">http://www.irf.com/package</a>

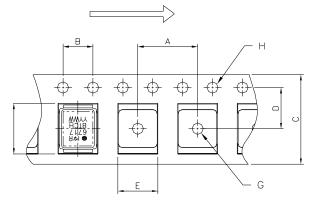
## DirectFET™ Tape & Reel Dimension (Showing component orientation).



NOTE: Controlling dimensions in mm Std reel quantity is 4800 parts. (ordered as IRF6717MTRPBF). For 1000 parts on 7" reel, order IRF6717MTR1PBF

	REEL DIMENSIONS									
S.	TANDARI	OPTION	I (QTY 48	00)	TR	1 OPTION	(QTY 10	00)		
	ME	TRIC	IMP	ERIAL	ME	TRIC	IMP	ERIAL		
CODE	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX		
Α	330.0	N.C	12.992	N.C	177.77	N.C	6.9	N.C		
В	20.2	N.C	0.795	N.C	19.06	N.C	0.75	N.C		
С	12.8	13.2	0.504	0.520	13.5	12.8	0.53	0.50		
D	1.5	N.C	0.059	N.C	1.5	N.C	0.059	N.C		
Е	100.0	N.C	3.937	N.C	58.72	N.C	2.31	N.C		
F	N.C	18.4	N.C	0.724	N.C	13.50	N.C	0.53		
G	12.4	14.4	0.488	0.567	11.9	12.01	0.47	N.C		
Н	11.9	15.4	0.469	0.606	11.9	12.01	0.47	N.C		

#### LOADED TAPE FEED DIRECTION



NOTE: CONTROLLING DIMENSIONS IN MM

DIMENSIONS								
	MET	RIC	IMPE	RIAL				
CODE	MIN	MAX	MIN	MAX				
Α	7.90	8.10	0.311	0.319				
В	3.90	4.10	0.154	0.161				
С	11.90	12.30	0.469	0.484				
D	5.45	5.55	0.215	0.219				
E	5.10	5.30	0.201	0.209				
F	6.50	6.70	0.256	0.264				
G	1.50	N.C	0.059	N.C				
Н	1.50	1.60	0.059	0.063				

Note: For the most current drawing please refer to IR website at <a href="http://www.irf.com/package">http://www.irf.com/package</a>

Data and specifications subject to change without notice. This product has been designed and qualified for the Consumer market. Qualification Standards can be found on IR's Web site.



IR WORLD HEADQUARTERS: 233 Kansas St., El Segundo, California 90245, USA Tel: (310) 252-7105 TAC Fax: (310) 252-7903